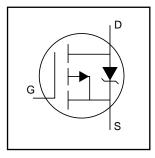
# International TOR Rectifier

## IRFR/U5505

#### HEXFET® Power MOSFET

- Ultra Low On-Resistance
- P-Channel
- Surface Mount (IRFR5505)
- Straight Lead (IRFU5505)
- Advanced Process Technology
- Fast Switching
- Fully Avalanche Rated



# $V_{DSS} = -55V$ $R_{DS(on)} = 0.11\Omega$ $I_{D} = -18A$

#### **Description**

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The D-Pak is designed for surface mounting using vapor phase, infrared, or wave soldering techniques. The straight lead version (IRFU series) is for through-hole mounting applications. Power dissipation levels up to 1.5 watts are possible in typical surface mount applications.



#### **Absolute Maximum Ratings**

|   | Parameter  | Max.                   | Units |  |
|---|--|------------------------|-------|--|
| I <sub>D</sub> @ T <sub>C</sub> = 25°C  | Continuous Drain Current, V <sub>GS</sub> @ -10V | -18                    |       |  |
| I <sub>D</sub> @ T <sub>C</sub> = 100°C | Continuous Drain Current, V <sub>GS</sub> @ -10V | -11                    | A     |  |
| I <sub>DM</sub>                         | Pulsed Drain Current ①                           | -64                    |       |  |
| P <sub>D</sub> @T <sub>C</sub> = 25°C   | Power Dissipation                                | 57                     | W     |  |
|   | Linear Derating Factor                           | 0.45                   | W/°C  |  |
| $V_{GS}$                                | Gate-to-Source Voltage                           | ± 20                   | V     |  |
| E <sub>AS</sub>                         | Single Pulse Avalanche Energy <sup>②</sup>       | 150                    | mJ    |  |
| I <sub>AR</sub>                         | Avalanche Current①                               | -9.6                   | A     |  |
| E <sub>AR</sub>                         | Repetitive Avalanche Energy ①                    | 5.7                    | mJ    |  |
| dv/dt                                   | Peak Diode Recovery dv/dt ③                      | -5.0                   | V/ns  |  |
| TJ                                      | Operating Junction and                           | -55 to + 150           |       |  |
| T <sub>STG</sub>                        | Storage Temperature Range                        |                        | °C    |  |
|   | Soldering Temperature, for 10 seconds            | 300 (1.6mm from case ) |       |  |

#### Thermal Resistance

|                 | Parameter                         | Тур. | Max. | Units |
|-----------------|-----------------------------------|------|------|-------|
| $R_{	heta JC}$  | Junction-to-Case                  |      | 2.2  |       |
| $R_{\theta JA}$ | Junction-to-Ambient (PCB mount)** |      | 50   | °C/W  |
| $R_{\theta JA}$ | Junction-to-Ambient               |      | 110  |       |

### IRFR/U5505

#### Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

|                                   | Parameter                            | Min. | Тур.   | Max. | Units  | Conditions   |
|-----------------------------------|--------------------------------------|------|--------|------|--------|--|
| V <sub>(BR)DSS</sub>              | Drain-to-Source Breakdown Voltage    | -55  |        |      | V      | $V_{GS} = 0V, I_D = -250\mu A$                     |
| $\Delta V_{(BR)DSS}/\Delta T_{J}$ | Breakdown Voltage Temp. Coefficient  |      | -0.049 |      | V/°C   | Reference to 25°C, I <sub>D</sub> = -1mA           |
| R <sub>DS(on)</sub>               | Static Drain-to-Source On-Resistance |      |        | 0.11 | Ω      | V <sub>GS</sub> = -10V, I <sub>D</sub> = -9.6A ④   |
| V <sub>GS(th)</sub>               | Gate Threshold Voltage               | -2.0 |        | -4.0 | V      | $V_{DS} = V_{GS}, I_{D} = -250 \mu A$              |
| 9fs                               | Forward Transconductance             | 4.2  |        |      | S      | $V_{DS} = -25V, I_{D} = -9.6A$                     |
| l                                 | Drain-to-Source Leakage Current      |      |        | -25  | μΑ     | $V_{DS} = -55V, V_{GS} = 0V$                       |
| I <sub>DSS</sub>                  | Diali-10-30dice Leakage Current      |      |        | -250 | μΑ     | $V_{DS} = -44V, V_{GS} = 0V, T_{J} = 150^{\circ}C$ |
| Lana                              | Gate-to-Source Forward Leakage       |      |        | -100 | nA     | V <sub>GS</sub> = 20V                              |
| I <sub>GSS</sub>                  | Gate-to-Source Reverse Leakage       |      |        | 100  | IIA    | V <sub>GS</sub> = -20V                             |
| Qg                                | Total Gate Charge                    |      |        | 32   |        | $I_D = -9.6A$                                      |
| Q <sub>gs</sub>                   | Gate-to-Source Charge                |      |        | 7.1  | nC     | $V_{DS} = -44V$                                    |
| Q <sub>gd</sub>                   | Gate-to-Drain ("Miller") Charge      |      |        | 15   |        | $V_{GS}$ = -10V, See Fig. 6 and 13 $\oplus$        |
| t <sub>d(on)</sub>                | Turn-On Delay Time                   |      | 12     |      |        | $V_{DD} = -28V$                                    |
| t <sub>r</sub>                    | Rise Time                            |      | 28     |      | ns     | $I_D = -9.6A$                                      |
| t <sub>d(off)</sub>               | Turn-Off Delay Time                  |      | 20     |      | 115    | $R_G = 2.6\Omega$                                  |
| t <sub>f</sub>                    | Fall Time                            |      | 16     |      |        | $R_D = 2.8\Omega$ , See Fig. 10 @                  |
|                                   | Internal Drain Inductance            |      | 4.5    | 5 —  |        | Between lead,                                      |
| L <sub>D</sub>                    |                                      |      | 4.5    |      | , nl l | 6mm (0.25in.)                                      |
| L <sub>S</sub>                    | Internal Source Inductance           |      | 7.5    |      | nH     | from package                                       |
|                                   |                                      |      |        |      |        | and center of die contact® s                       |
| Ciss                              | Input Capacitance                    |      | 650    |      |        | V <sub>GS</sub> = 0V                               |
| Coss                              | Output Capacitance                   |      | 270    |      | pF     | $V_{DS} = -25V$                                    |
| C <sub>rss</sub>                  | Reverse Transfer Capacitance         |      | 120    |      |        | f = 1.0MHz, See Fig. 5                             |

#### **Source-Drain Ratings and Characteristics**

|                 | Parameter                 | Min.   | Тур.    | Max. | Units               | Conditions                                      |
|-----------------|---------------------------|--|---------|------|---------------------|---|
| Is              | Continuous Source Current |  |         | -18  |                     | MOSFET symbol                                   |
|                 | (Body Diode)              |  | -10     | A    | showing the         |   |
| I <sub>SM</sub> | Pulsed Source Current     |  |         | 64   |                     | integral reverse                                |
|                 | (Body Diode) ①            |  | -   -64 | 4    | p-n junction diode. |   |
| V <sub>SD</sub> | Diode Forward Voltage     |  |         | -1.6 | V                   | $T_J = 25$ °C, $I_S = -9.6$ A, $V_{GS} = 0$ V ④ |
| t <sub>rr</sub> | Reverse Recovery Time     |  | 51      | 77   | ns                  | $T_J = 25$ °C, $I_F = -9.6A$                    |
| Q <sub>rr</sub> | Reverse RecoveryCharge    |  | 110     | 160  | nC                  | di/dt = 100A/µs ④                               |
| t <sub>on</sub> | Forward Turn-On Time      | Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> ) |         |      |                     |   |

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 11 )
- $\begin{tabular}{ll} \hline @ Starting $T_J$ = 25°C, $L$ = 3.2mH \\ $R_G$ = 25$\Omega, $I_{AS}$ = -9.6A. (See Figure 12) \\ \hline \end{tabular}$
- $\ \Im \ I_{SD} \leq$  -9.6A, di/dt  $\leq$  290A/µs,  $V_{DD} \leq$   $V_{(BR)DSS},$   $T_{J} \leq$  150°C
- ⓐ Pulse width ≤ 300 $\mu$ s; duty cycle ≤ 2%.
- $\tilde{\mathbb{S}}$ This is applied for I-PAK, L<sub>S</sub> of D-PAK is measured between lead and center of die contact
- \*\* When mounted on 1" square PCB (FR-4 or G-10 Material ) .
  For recommended footprint and soldering techniques refer to application note #AN-994

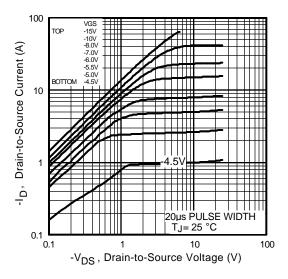


Fig 1. Typical Output Characteristics

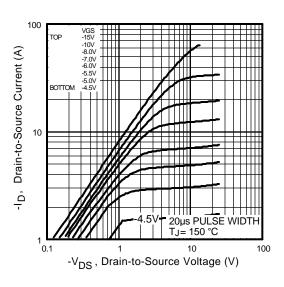


Fig 2. Typical Output Characteristics

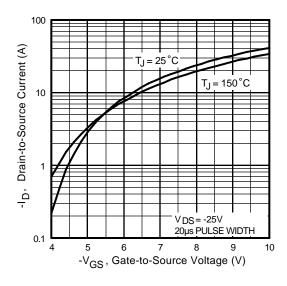
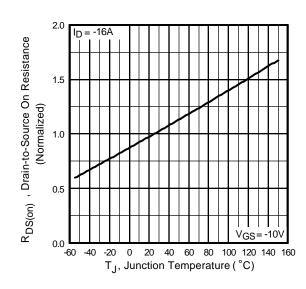
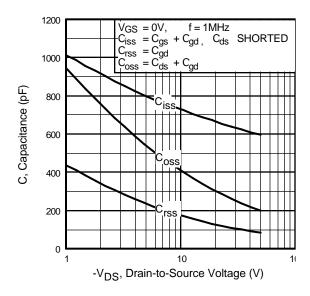


Fig 3. Typical Transfer Characteristics



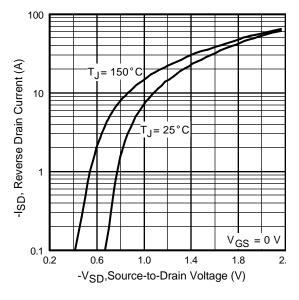
**Fig 4.** Normalized On-Resistance Vs. Temperature

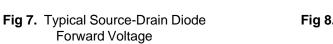


20  $I_{D} = -9.6A$ V<sub>DS</sub>=-44V, V<sub>DS</sub>=-28V, -V<sub>GS</sub>, Gate-to-Source Voltage (V) 16 12 8 4 FOR TEST CIRCUIT SEE FIGURE 13 0 10 0 20 30 40 Q<sub>G</sub>, Total Gate Charge (nC)

**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage

**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage





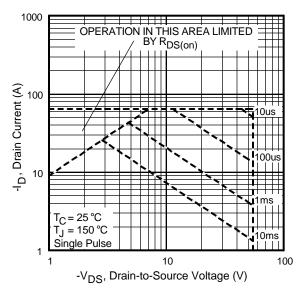
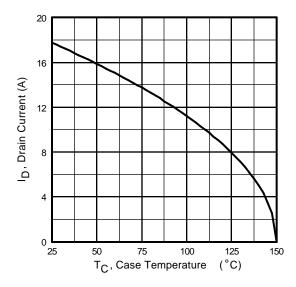


Fig 8. Maximum Safe Operating Area



**Fig 9.** Maximum Drain Current Vs. Case Temperature

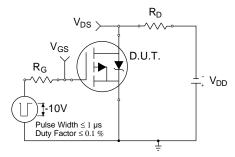


Fig 10a. Switching Time Test Circuit

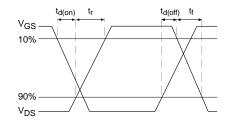


Fig 10b. Switching Time Waveforms

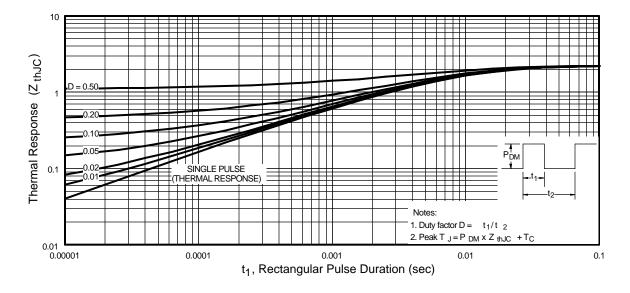


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

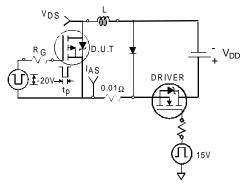


Fig 12a. Unclamped Inductive Test Circuit

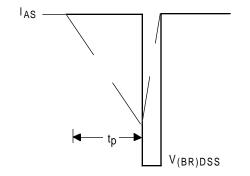


Fig 12b. Unclamped Inductive Waveforms

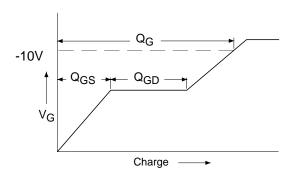
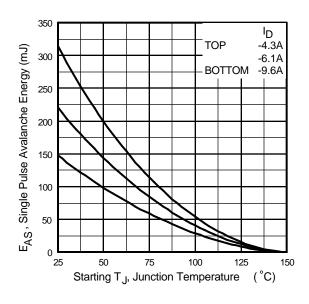


Fig 13a. Basic Gate Charge Waveform



**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current

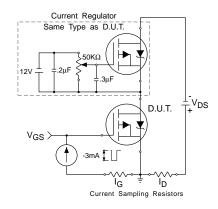
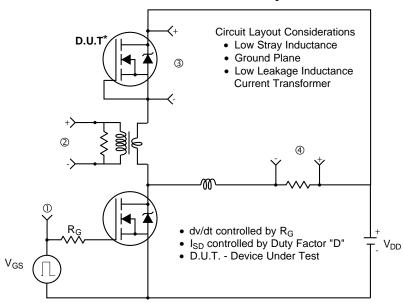
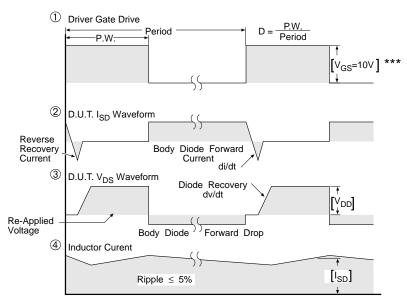


Fig 13b. Gate Charge Test Circuit

#### Peak Diode Recovery dv/dt Test Circuit



<sup>\*</sup> Reverse Polarity of D.U.T for P-Channel



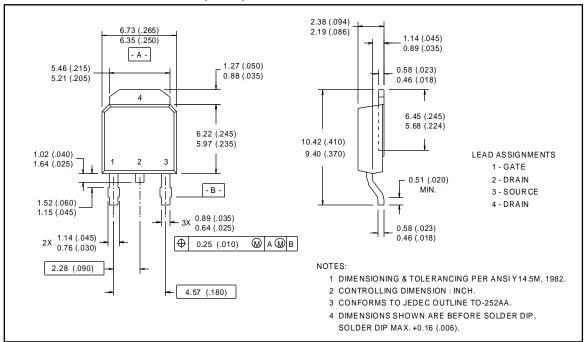
\*\*\* V<sub>GS</sub> = 5.0V for Logic Level and 3V Drive Devices

Fig 14. For P-Channel HEXFETS

#### Package Outline

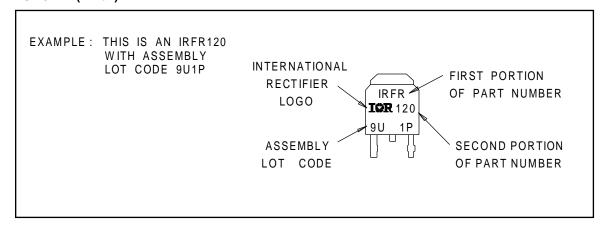
#### **TO-252AA Outline**

Dimensions are shown in millimeters (inches)



#### Part Marking Information

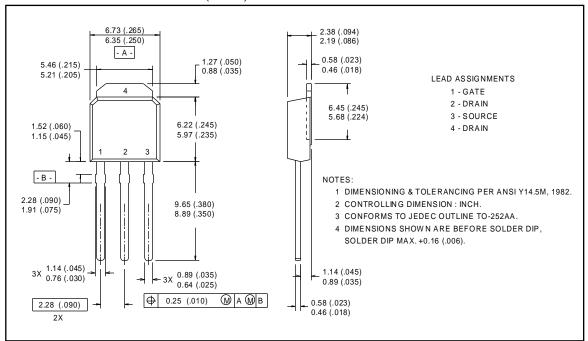
#### TO-252AA (D-Pak)



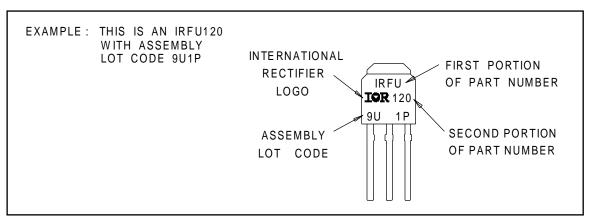
#### Package Outline

#### **TO-251AA Outline**

Dimensions are shown in millimeters (inches)

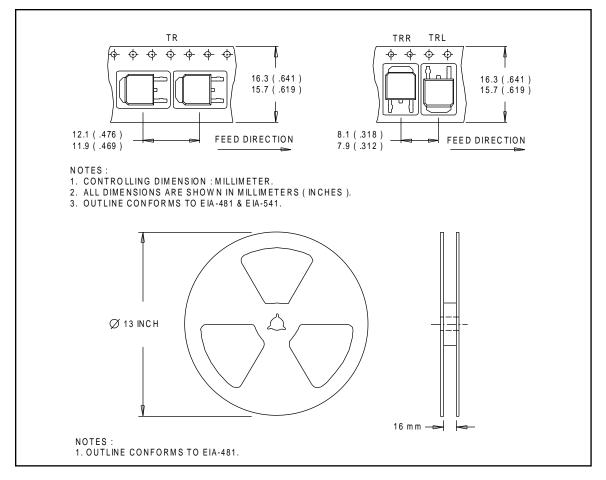


# Part Marking Information TO-251AA (I-Pak)



#### **Tape & Reel Information**

#### **TO-252AA**



# International IOR Rectifier

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